SILICON PLANAR EPITAXIAL TRANSISTOR

N-P-N transistor in a TO-18 metal envelope primarily intended for high-speed saturated switching and high frequency amplifier applications.

QUICK REFERENCE DATA

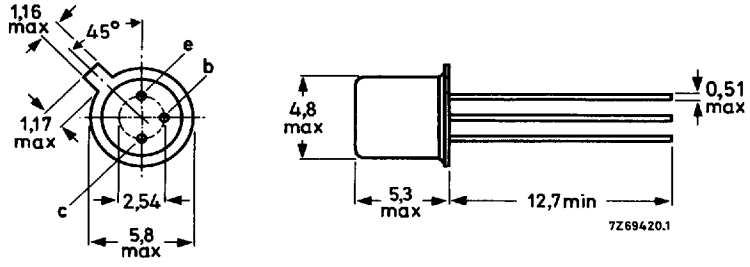
Collector-base voltage (open emitter)	V_{CBO}	max.	40	V
Collector-emitter voltage (open base)	V_{CEO}	max.	15	V
Collector current (peak value; t_p = 10 μs)	I_{CM}	max.	500	mA
Total power dissipation up to T_{amb} = 25 °C	P_{tot}	max.	360	mW
Junction temperature	T_j	max.	200	°C
D.C. current gain at T_j = 25 °C				
I_C = 10 mA; V_{CE} = 0,35 V	h_{FE}	>	40	
I_C = 10 mA; V_{CE} = 1,0 V	h_{FE}	<	120	
Transition frequency at f = 100 MHz				
I_C = 10 mA; V_{CE} = 10 V	f_T	>	500	MHz
Storage time				
$I_{Con} = I_{Bon} = -I_{Boff}$ = 10 mA	t_s	<	13	ns

MECHANICAL DATA

Dimensions in mm

Fig. 1 TO-18.

Collector connected to case.



RATINGS

Limiting values in accordance with the Absolute Maximum System (IEC 134)

Collector-base voltage (open emitter)	V_{CBO}	max.	40	V
Collector-emitter voltage (open base) I_C = 0,01 mA to 10 mA	V_{CEO}	max.	15	V
Collector-emitter voltage (V_{BE} = 0)	V_{CES}	max.	40	V
Emitter-base voltage (open collector)	V_{EBO}	max.	4,5	V
Collector current (d.c.)	I_C	max.	200	mA
Collector current (peak value; t_p = 10 μs)	I_{CM}	max.	500	mA
Total power dissipation up to T_{amb} = 25 °C	P_{tot}	max.	360	mW
up to T_{case} = 25 °C	P_{tot}	max.	1200	mW
up to T_{case} = 100 °C	P_{tot}	max.	680	mW
Storage temperature range	T_{stg}	−65 to +	150	°C
Junction temperature	T_j	max.	200	°C

THERMAL RESISTANCE

From junction to ambient in free air	$R_{th\ j\text{-}a}$	=	486	K/W
From junction to case	$R_{th\ j\text{-}c}$	=	146	K/W

CHARACTERISTICS

T_{amb} = 25 °C unless otherwise specified

Collector cut-off current			
V_{BE} = 0; V_{CE} = 20 V	I_{CES}	<	0,4 μA
I_E = 0; V_{CB} = 20 V; T_{amb} = 150 °C	I_{CBO}	<	30 μA
Base current			
V_{BE} = 0; V_{CE} = 20 V	$-I_{BEX}$	<	0,4 μA
Collector-base breakdown voltage			
open emitter; I_C = 10 μA	$V_{(BR)CBO}$	>	40 V
Collector-emitter breakdown voltage			
V_{BE} = 0; I_C = 10 μA	$V_{(BR)CES}$	>	40 V
Emitter-base breakdown voltage			
open collector; I_E = 10 μA	$V_{(BR)EBO}$	>	4,5 V
Collector-emitter sustaining voltage*			
open base; I_C = 10 mA	$V_{CEOsust}$	>	15 V
Saturation voltages			
I_C = 10 mA; I_B = 1,0 mA	V_{CEsat}	<	0,20 V
	V_{BEsat}		0,70 to 0,85 V
I_C = 10 mA; I_B = 1,0 mA; T_{amb} = 125 °C	V_{CEsat}	<	0,30 V
	V_{BEsat}	>	0,59 V
I_C = 10 mA; I_B = 1,0 mA; T_{amb} = −55 °C	V_{BEsat}	<	1,02 V
I_C = 30 mA; I_B = 3,0 mA	V_{CEsat}	<	0,25 V
	V_{BEsat}	<	1,15 V
I_C = 100 mA; I_B = 10 mA	V_{CEsat}	<	0,50 V
	V_{BEsat}	<	1,60 V
D.C. current gain*			
I_C = 10 mA; V_{CE} = 0,35 V	h_{FE}	>	40
I_C = 10 mA; V_{CE} = 0,35 V; T_{amb} = −55 °C	h_{FE}	>	20
I_C = 10 mA; V_{CE} = 1,0 V	h_{FE}	<	120
I_C = 30 mA; V_{CE} = 0,4 V	h_{FE}	>	30
I_C = 100 mA; V_{CE} = 1,0 V	h_{FE}	>	20
Collector capacitance at f = 140 kHz			
$I_E = I_e$ = 0; V_{CB} = 5,0 V	C_c	<	4,0 pF
Transition frequency at f = 100 MHz			
I_C = 10 mA; V_{CE} = 10 V	f_T	>	500 MHz

* Measured under pulse conditions to avoid excessive dissipation: t_p = 300 μs; $\delta \leqslant 0{,}02$.

Storage time (see Figs 2 and 3)

$I_{Con} = I_{Bon} = -I_{Boff} = 10$ mA

t_s < 13 ns

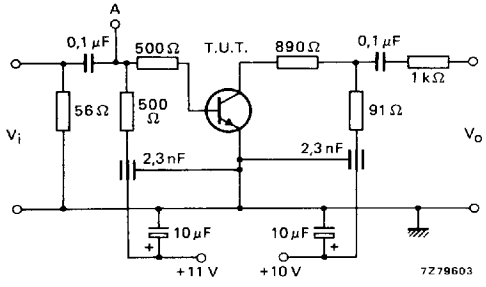


Fig. 2 Storage time test circuit.

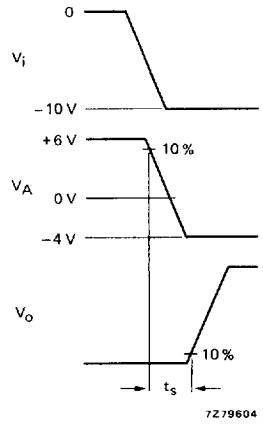


Fig. 3 Waveforms at input, point A and output.

Turn-on time (see Figs 4 and 5)

$I_{Con} = 10$ mA; $I_{Bon} = 3$ mA; $-V_{BEoff} = 1{,}5$ V

t_{on} < 12 ns

Turn-off time (see Figs 4 and 5)

$I_{Con} = 10$ mA; $I_{Bon} = 3$ mA; $-I_{Boff} = 1{,}5$ mA

t_{off} < 18 ns

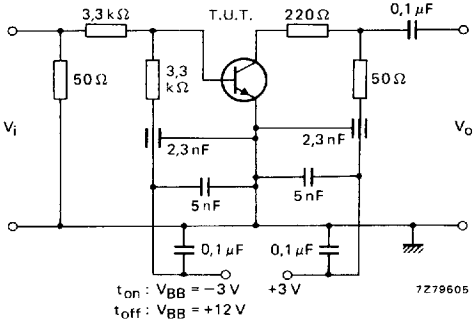


Fig. 4 Turn-on and turn-off test circuit.

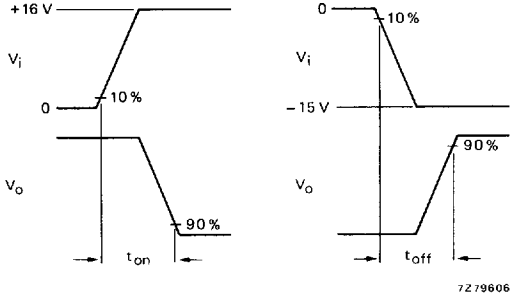


Fig. 5 Input and output waveforms.

Pulse generator:

Rise time	t_r	⩽	1 ns
Pulse duration	t_p	⩾	300 ns
Duty factor	δ	⩽	0,02
Source impedance	R_S	=	50 Ω

Oscilloscope:

Rise time	t_r	⩽	1 ns
Input impedance	R_i	=	50 Ω